

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

 ATTY. DOCKET NO.
044117-0143

 SERIAL NO.
10/539,771

 APPLICANT
Eric PINET, et al.

 FILING DATE
January 10, 2006

 GROUP
1797

(Substitute for form 1449/PTO)

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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						Yes No

OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)

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